

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination OHNO ET AL.	
		Examiner KARUNA P. REDDY	Art Unit 1796	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,964,999 B1	11-2005	Nakagawa et al.	525/193
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D	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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